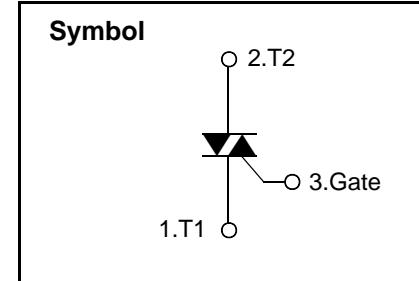
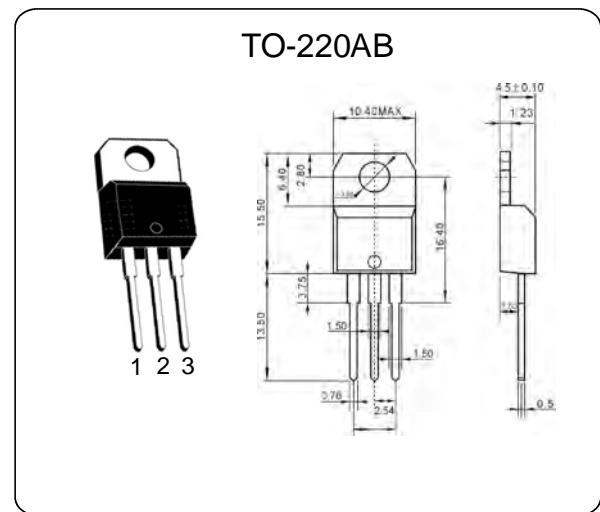


## **Bi-Directional Triode Thyristor**

Designed for high performance full-wave ac control applications where high noise immunity and high commutating di/dt are required.

### **Features**

- Blocking Voltage to 800 V
- On-State Current Rating of 16A RMS at 80°C
- Uniform Gate Trigger Currents in Three Quadrants
- High Immunity to dV/dt-1500V/us minimum at 125°C
- Minimizes Snubber Networks for Protection
- Industry Standard TO-220AB Package
- High Commutating di/dt- 4.0A/ms minimum at 125°C
- Internally Isolated (2500VRMS)
- These are Pb-Free Devices



### **Absolute Maximum Ratings**

Symbol	Parameter		Value	Unit
$I_{T(RMS)}$	RMS on-state current(full sine wave)	TO-220AB	16	A
		TO-220AB Ins.		
$I_{TSM}$	Non repetitive surge peak on-state current(full cycle, $T_j$ initial=25°C)	F=50Hz	t=20ms	A
		F=60Hz	t=16.7ms	
$I^2t$	$I^2t$ Value for fusing	tp=10ms		144 $A^2s$
DI/DT	Critical rate of rise of on-state current $IG=2X_{IGT,tr \leq 100ns}$	F=120Hz	$T_j=125^\circ C$	50 $A/us$
VDSM/V RSM	Non repetitive surge peak off-state voltage	tp=10ms	$T_j=25^\circ C$	$V_{drm} / v_{rrm} + 100V$ V
IGM	Peak gate current	tp=20us	$T_j=125^\circ C$	4 A
$P_{G(AV)}$	Average gate power dissipation	$T_j=125^\circ C$		1 W
$T_{stg}$	Storage junction temperature range	-40 to +150		$^\circ C$
$T_j$	Operating junction temperature range	-40 to +125		



# BTA16-800C

## Electrical Characteristics( $T_j=25^\circ\text{C}$ ,unless otherwise specified)

### Snubberless™ and Logic Level (3 quadrants)

Symbol	Test conditions	Quadrant	BTA16-800C		Unit
$I_{GT}(1)$	$V_D=12V \quad R_L=33\Omega$	I - II - III	MAX	35	mA
$V_{GT}$		I - II - III	MAX	1.3	V
$V_{GD}$	$V_D=V_{DRM} \quad R_L=3.3K\Omega \quad T_j=125^\circ\text{C}$	I - II - III	MIN	0.2	V
$I_{H(2)}$	$I_T=500\text{mA}$ $I_G=1.2I_{GT}$	I - III II	MAX	50	mA
$I_L$			MAX	70	mA
				80	
$Dv / Dt(2)$	$V_D=67\%V_{DRM}$ Gate open $T_j=125^\circ\text{C}$		MIN	1000	V/us
$(Dl/dt)c(2)$	$(Dv/dt)c=0.1V/\text{us} \quad T_j=125^\circ\text{C}$		MIN	-	A/ms
	$(Dv/dt)c=10V/\text{us} \quad T_j=125^\circ\text{C}$			-	
	Without snubber $T_j=125^\circ\text{C}$			14	

### Standard (4 Quadrants)

Symbol	Test conditions	Quadrant	BTA16-800C		Unit
$I_{GT}(1)$	$V_D=12V \quad R_L=33\Omega$	I - II - III	MAX	35	mA
$V_{GT}$		IV		50	
$V_{GD}$	$V_D=V_{DRM} \quad R_L=3.3K\Omega \quad T_j=125^\circ\text{C}$	ALL	MAX	1.3	V
$I_{H(2)}$	$I_T=500\text{mA}$		MIN	0.2	V
$I_L$	$I_G=1.2I_{GT}$	I - III - IV	MAX	60	mA
		II		120	
$(Dl/dt)(2)$	$V_D=67\%V_{DRM}$ Gate open $T_j=125^\circ\text{C}$		MIN	400	V/us
$(Dl/dt)c(2)$	$(Dv/dt)c=7A/\text{ms} \quad T_j=125^\circ\text{C}$		MIN	10	V/us

### Static Characteristics

Symbol	Test conditions			Value	Unit
$VTM(2)$	$ITM=22A \quad tp=380\mu\text{s}$	$TJ=25^\circ\text{C}$	MAX	1.55	V
$Vto(2)$	Threshold voltage	$TJ=125^\circ\text{C}$	MAX	0.85	V
$Rd(2)$	Dynamic resistance	$TJ=125^\circ\text{C}$	MAX	25	$\text{m}\Omega$
$I_{DRM}$ $I_{RRM}$	$V_{DRM}=V_{RRM}$	$TJ=25^\circ\text{C}$	MAX	5	$\mu\text{A}$
		$TJ=125^\circ\text{C}$		2	mA
$V_{DRM}/V_{RRM}$	Voltage	$TJ=25^\circ\text{C}$	MIN	800	V

Note 1: minimum IGT is guaranteed at 5% of IGT max

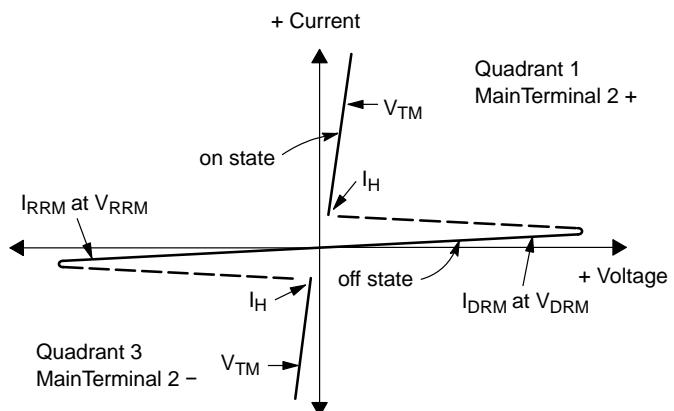
Note 2: for both polarities of A2 referenced to A1

### Thermal Resistances

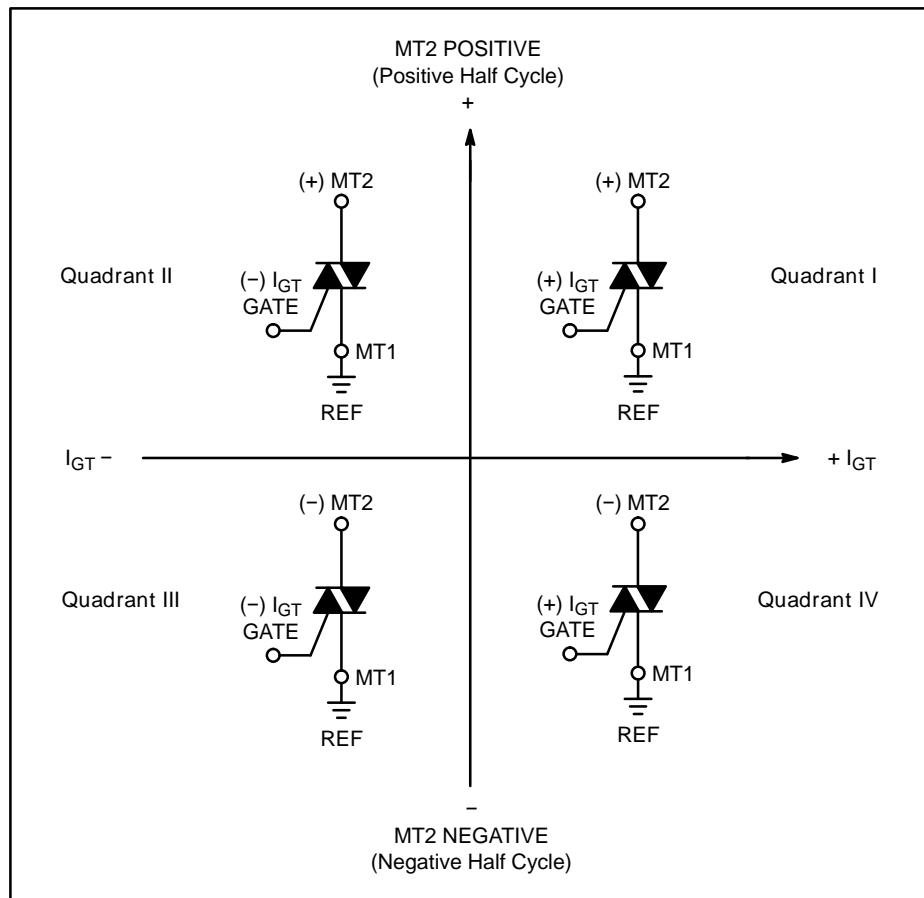
Symbol	Parameter	Value	Unit
$R_{lh(j-c)}$	Junction to case(AC)	TO-220AB	1.2
		TO-220AB(Insulated)	2.1
$R_{th(j-a)}$	Junction to ambient	TO-220AB/ TO-220AB(Insulated)	60
			°C/W

## Voltage Current Characteristic of Triacs (Bidirectional Device)

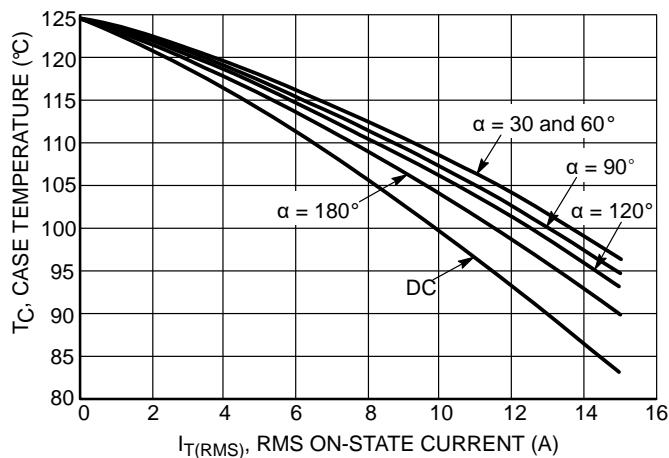
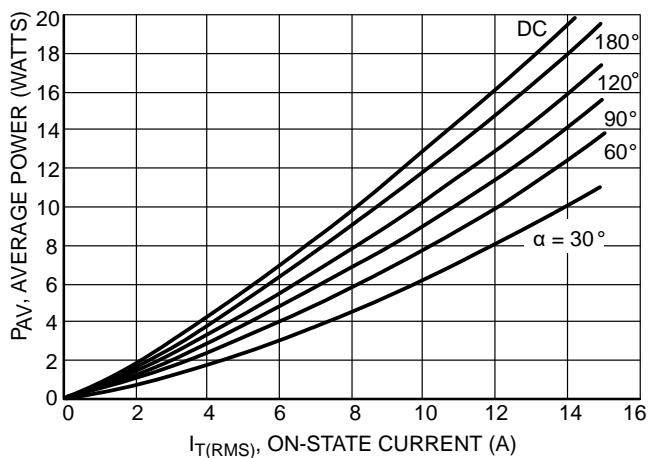
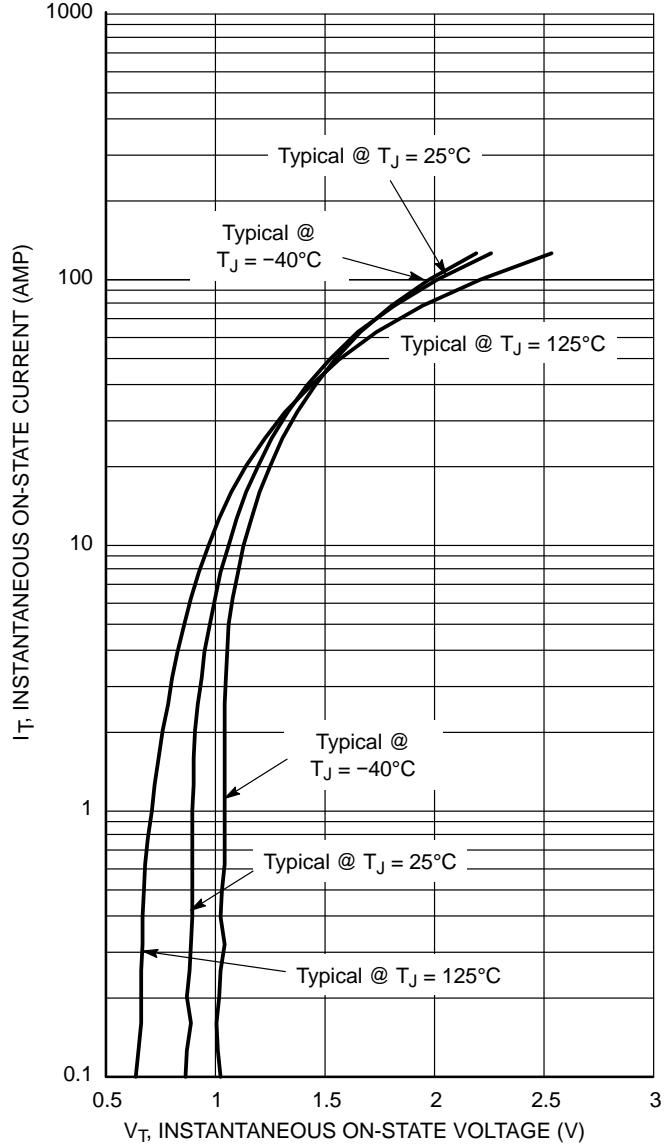
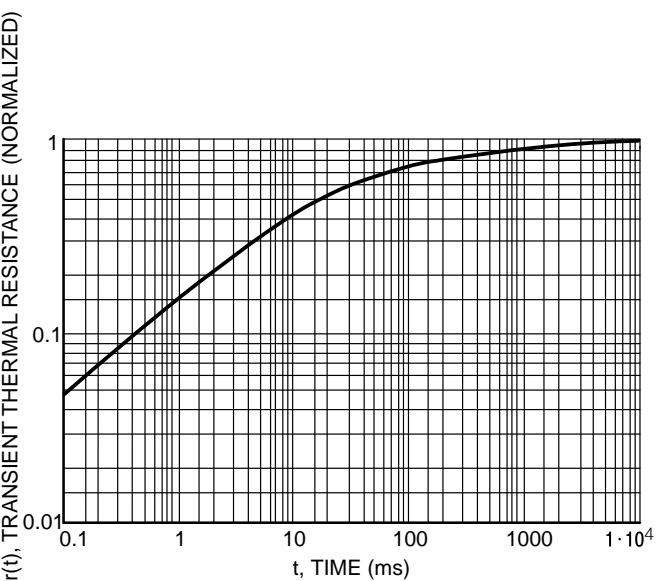
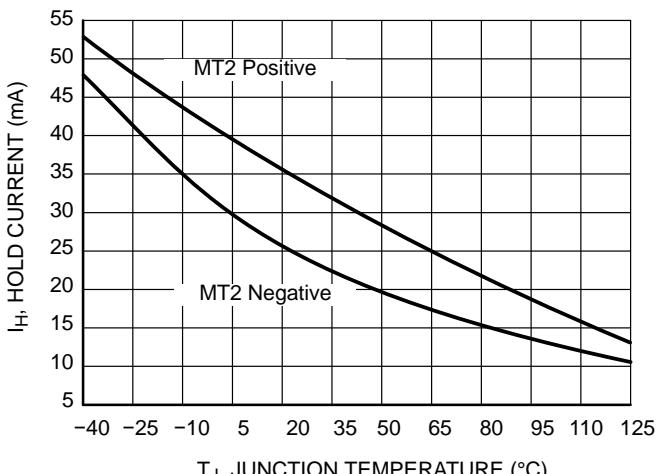
Symbol	Parameter
$V_{DRM}$	Peak Repetitive Forward Off State Voltage
$I_{DRM}$	Peak Forward Blocking Current
$V_{RRM}$	Peak Repetitive Reverse Off State Voltage
$I_{RRM}$	Peak Reverse Blocking Current
$V_{TM}$	Maximum On State Voltage
$I_H$	Holding Current



Quadrant Definitions for a Triac



All polarities are referenced to MT1.  
With in-phase signals (using standard AC lines) quadrants I and III are used.


**Figure 1. RMS Current Derating**

**Figure 2. On-State Power Dissipation**

**Figure 3. On-State Characteristics**

**Figure 4. Thermal Response**

**Figure 5. Hold Current Variation**

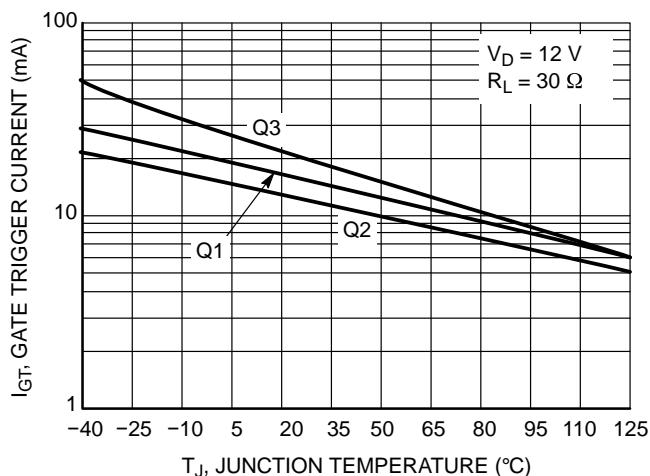


Figure 6. Gate Trigger Current Variation

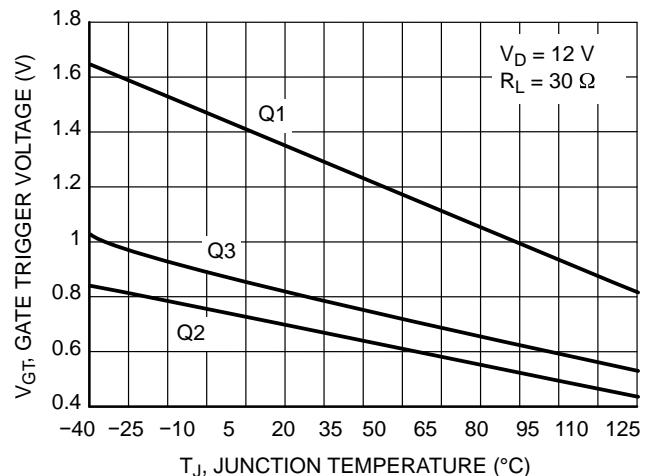


Figure 7. Gate Trigger Voltage Variation

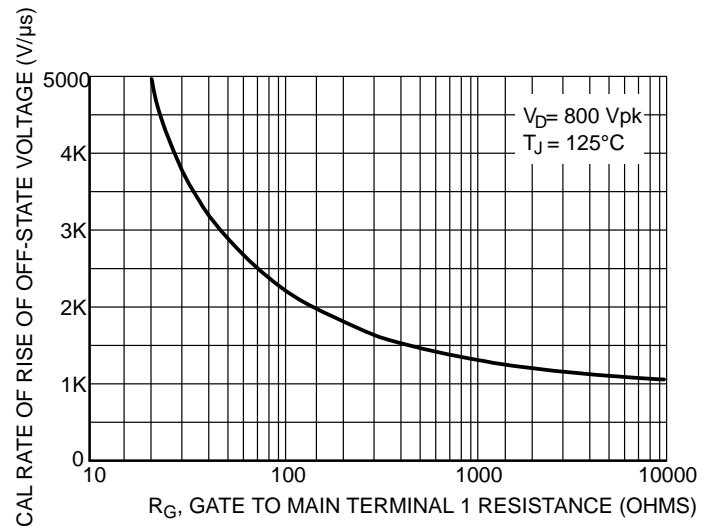
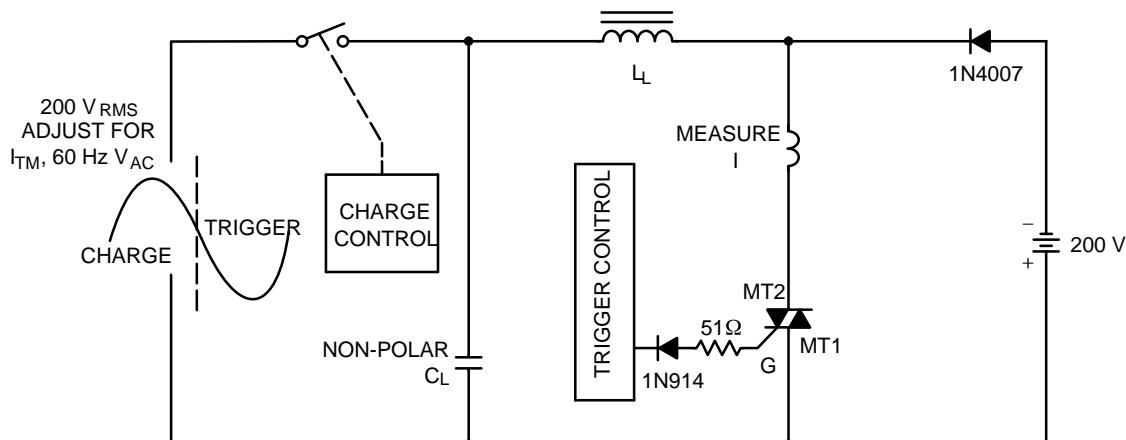


Figure 8. Critical Rate of Rise of Off-State Voltage  
(Exponential Waveform)



Note: Component values are for verification of rated  $(di/dt)_c$ . See AN1048 for additional information.

Figure 9. Simplified Test Circuit to Measure the Critical Rate of Rise of Commutating Current ( $di/dt_c$ )